
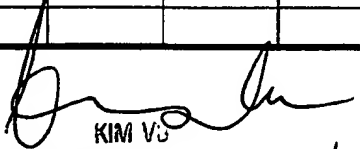



Issue Classification 	Application/Control No.		Applicant(s)/Patent under Reexamination	
	09/614,087		LEAH ET AL.	
	Examiner		Art Unit	
	Tongoc Tran		2134	

ISSUE CLASSIFICATION										
ORIGINAL				CROSS REFERENCE(S)						
CLASS		SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)					
713		155		713	161	169	170	184	201	202
INTERNATIONAL CLASSIFICATION				380	274					
H	0	4	L	9/00	709	206	246			
				/						
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				/						
Tongoc Tran 6/27/2005 (Assistant Examiner) (Date)				 KIM VU SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER (Primary Examiner) (Date) 6/27/05				34 Total Claims Allowed: 36		
 John E. Bruce 6/27/05 (Legal Instruments Examiner) (Date)								O.G. Print Claim(s) 1	O.G. Print Fig. Fig. 6	

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<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
Final	Original	Final	Original	Final	Original	Final	Original
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	3	23	33				
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